

# **MPG Halbleiterlabor Review**



## **Report of Contributions**

Contribution ID: 0

Type: **not specified**

## Welcome and introduction

*Monday, 19 December 2016 08:30 (30 minutes)*

**Presenter:** NINKOVIC, Jelena (MPG Halbleiterlabor)

**Session Classification:** Technology I

Contribution ID: 1

Type: **not specified**

# Introduction in Technology, Process Plans and Organisation

*Monday, 19 December 2016 09:00 (30 minutes)*

**Presenter:** SCHALLER, Gerhard

**Session Classification:** Technology I

Contribution ID: 2

Type: **not specified**

## **Clean Room Rules and Security**

*Monday, 19 December 2016 09:30 (30 minutes)*

**Presenter:** SCHNECKE, Martina

**Session Classification:** Technology I

Contribution ID: 3

Type: **not specified**

## **CAD/Waferhandling**

*Monday, 19 December 2016 10:00 (30 minutes)*

**Presenter:** FUCHS, Gerhard

**Session Classification:** Technology I

Contribution ID: 4

Type: **not specified**

# Litography

*Monday, 19 December 2016 11:00 (30 minutes)*

**Presenter:** BURKHARDT, Anne

**Session Classification:** Technology II

Contribution ID: 5

Type: **not specified**

## Wet Chemistry

*Monday, 19 December 2016 11:30 (30 minutes)*

**Presenter:** JENSEN, Sven

**Session Classification:** Technology II

Contribution ID: 6

Type: **not specified**

## Oven and LPCVD technique

*Monday, 19 December 2016 12:00 (30 minutes)*

**Presenter:** ZIRR, Christian

**Session Classification:** Technology II



Contribution ID: 7

Type: **not specified**

## **Plasma processes**

*Monday, 19 December 2016 14:00 (30 minutes)*

**Presenter:** SCHOPPER, Florian

**Session Classification:** Technology III

Contribution ID: 8

Type: **not specified**

## **Ion Implantations**

*Monday, 19 December 2016 14:30 (30 minutes)*

**Presenter:** MATIASKE, Mark

**Session Classification:** Technology III

Contribution ID: 9

Type: **not specified**

## Galvanic process

*Monday, 19 December 2016 15:00 (30 minutes)*

**Presenter:** SCHEUGENPFLUG, Eva

**Session Classification:** Technology III

Contribution ID: **10**

Type: **not specified**

## **Measurement techniques**

*Monday, 19 December 2016 15:30 (30 minutes)*

**Presenter:** ZIRR, Christian

**Session Classification:** Technology III

Contribution ID: 11

Type: **not specified**

## High Energy Physics - selected topics

*Tuesday, 20 December 2016 08:30 (1 hour)*

**Presenter:** Prof. BETHKE, S. (Max Planck Institute für Physik)

**Session Classification:** Morning Session

Contribution ID: 12

Type: **not specified**

## **Planarisation - SOG**

*Tuesday, 20 December 2016 09:30 (25 minutes)*

**Presenter:** SCHEUGENPFLUG, Eva

**Session Classification:** Future technology I

Contribution ID: 13

Type: **not specified**

## **Planarisation - CMP**

*Tuesday, 20 December 2016 09:55 (25 minutes)*

**Presenter:** LEHMANN, Raik

**Session Classification:** Future technology I

Contribution ID: 14

Type: **not specified**

## **New processes**

*Tuesday, 20 December 2016 11:00 (45 minutes)*

**Presenter:** SCHOPPER, Florian

**Session Classification:** Future technology II



Contribution ID: 15

Type: **not specified**

## **Brainstorming - Technology plans for the next 10 years**

*Tuesday, 20 December 2016 11:45 (45 minutes)*

**Session Classification:** Future technology II

Contribution ID: 16

Type: **not specified**

## Standard Test Devices

*Tuesday, 20 December 2016 14:00 (30 minutes)*

**Presenter:** LECHNER, Peter

**Session Classification:** Wafer level testing

Contribution ID: 17

Type: **not specified**

## Device testing on wafer level

*Tuesday, 20 December 2016 14:30 (30 minutes)*

**Presenter:** KLOSE, Daniel

**Session Classification:** Wafer level testing

Contribution ID: **18**

Type: **not specified**

## **Flying prober**

*Tuesday, 20 December 2016 15:00 (30 minutes)*

**Presenter:** KOFFMANE, Christian (MPI Halbleiterlabor)

**Session Classification:** Wafer level testing

Contribution ID: 19

Type: **not specified**

## **PHEMOS investigations**

*Tuesday, 20 December 2016 15:30 (30 minutes)*

**Presenter:** NINKOVIC, Jelena (MPG Halbleiterlabor)

**Session Classification:** Wafer level testing

Contribution ID: 20

Type: **not specified**

## **HLL IT structure**

*Tuesday, 20 December 2016 16:30 (30 minutes)*

**Presenter:** JAKOWITSCH, Jorma

**Session Classification:** From Sensors to Detectors

Contribution ID: 21

Type: **not specified**

## **ASICs developments**

*Tuesday, 20 December 2016 17:00 (30 minutes)*

**Presenter:** WASSATSCH, Andreas

**Session Classification:** From Sensors to Detectors

Contribution ID: 22

Type: **not specified**

## **HLL Modular DAQ system**

*Tuesday, 20 December 2016 18:00 (30 minutes)*

**Presenter:** TREIS, Johannes

**Session Classification:** From Sensors to Detectors



Contribution ID: 23

Type: **not specified**

## **Module Interconnection Concepts**

*Tuesday, 20 December 2016 17:30 (30 minutes)*

**Presenter:** ANDRICEK, Laci (MPG Halbleiterlabor)

**Session Classification:** From Sensors to Detectors

Contribution ID: 24

Type: **not specified**

## **Processes and Tools in the Applicationlab**

*Monday, 19 December 2016 16:30 (30 minutes)*

**Presenter:** LIEMANN, Gerhard

**Session Classification:** Technology IV

Contribution ID: 25

Type: **not specified**

## **Lasercutting: Status and perspectives**

*Monday, 19 December 2016 17:00 (30 minutes)*

**Presenter:** MATIASKE, Mark

**Session Classification:** Technology IV

Contribution ID: 26

Type: **not specified**

## **Flip-Chip and SMD**

*Monday, 19 December 2016 18:00 (30 minutes)*

**Presenter:** KRIVOKUCA, Silvia

**Session Classification:** Technology IV

Contribution ID: 27

Type: **not specified**

## **Assembly and interconnection technology**

*Monday, 19 December 2016 17:30 (30 minutes)*

**Presenter:** MIESSNER, Danilo

**Session Classification:** Technology IV

Contribution ID: **28**

Type: **not specified**

## **BELLE II detector**

*Tuesday, 20 December 2016 20:00 (1 hour)*

**Presenter:** MARINAS, Carlos (University of Bonn)

**Session Classification:** Evening Talk

Contribution ID: 29

Type: **not specified**

## **HLL devices**

*Wednesday, 21 December 2016 08:30 (30 minutes)*

**Presenter:** LECHNER, Peter

**Session Classification:** Devices and Simulations

Contribution ID: **30**

Type: **not specified**

## **Device and technology simulations**

*Wednesday, 21 December 2016 09:30 (1 hour)*

**Presenter:** RICHTER, Rainer (MPI)

**Session Classification:** Devices and Simulations



Contribution ID: **31**

Type: **not specified**

## **Belle II PXD - Scientific motivation**

*Wednesday, 21 December 2016 12:00 (30 minutes)*

**Presenter:** Prof. KIESLING, Christian (Max-Planck-Institute for Physics)

**Session Classification:** Projects I

Contribution ID: 32

Type: **not specified**

## **Belle II PXD - detector description**

*Wednesday, 21 December 2016 14:00 (30 minutes)*

**Presenter:** KOFFMANE, Christian (MPI Halbleiterlabor)

**Session Classification:** Projects II

Contribution ID: 33

Type: **not specified**

## **GREST project**

*Wednesday, 21 December 2016 11:30 (30 minutes)*

**Presenter:** BAEHR, Alexander

**Session Classification:** Projects I

Contribution ID: 34

Type: **not specified**

## **ATHENA WFI - scientific motivation**

*Wednesday, 21 December 2016 14:30 (30 minutes)*

**Primary author:** RAU, Arne

**Presenter:** RAU, Arne

**Session Classification:** Projects II

Contribution ID: 35

Type: **not specified**

## **ATHENA WFI - detector description**

*Wednesday, 21 December 2016 15:00 (30 minutes)*

**Presenter:** BAEHR, Alexander

**Session Classification:** Projects II

Contribution ID: 36

Type: **not specified**

## **FSP - scientific motivation**

**Presenter:** FELLER, Alex

Contribution ID: 37

Type: **not specified**

## **FSP - detector**

*Wednesday, 21 December 2016 11:00 (30 minutes)*

**Presenter:** SELLE, Thomas

**Session Classification:** Projects I

Contribution ID: **38**

Type: **not specified**

## **Edet - scientific motivation**

*Wednesday, 21 December 2016 15:30 (30 minutes)*

**Presenter:** EPP, Sascha

**Session Classification:** Projects II



Contribution ID: **39**

Type: **not specified**

## **Edet - detector**

*Wednesday, 21 December 2016 16:30 (30 minutes)*

**Presenter:** TREIS, Johannes

**Session Classification:** Projects III

Contribution ID: 40

Type: **not specified**

## **TRISTAN project**

*Wednesday, 21 December 2016 17:00 (30 minutes)*

**Presenter:** LECHNER, Peter

**Session Classification:** Projects III

Contribution ID: 41

Type: **not specified**

## **Photon sensors characterisation tools**

*Thursday, 22 December 2016 09:00 (30 minutes)*

**Presenter:** PETROVICS, Stefan

**Session Classification:** Projects IV

Contribution ID: 42

Type: **not specified**

## **Simpl & dSiMPI**

*Thursday, 22 December 2016 09:30 (30 minutes)*

**Presenter:** PETROVICS, Stefan

**Session Classification:** Projects IV

Contribution ID: 43

Type: **not specified**

## **Small pixel pnCCDs for Xray imaging**

*Thursday, 22 December 2016 10:25 (25 minutes)*

**Presenter:** SCHOPPER, Florian

**Session Classification:** Projects IV

Contribution ID: 44

Type: **not specified**

## **APDs for X-ray imaging**

*Thursday, 22 December 2016 10:00 (25 minutes)*

**Presenter:** RICHTER, Rainer (MPI)

**Session Classification:** Projects IV

Contribution ID: 45

Type: **not specified**

## Wrap-up

*Thursday, 22 December 2016 10:50 (10 minutes)*

**Presenter:** NINKOVIC, Jelena (MPG Halbleiterlabor)

**Session Classification:** Projects IV

Contribution ID: 46

Type: **not specified**

## **Recent advances in IGBT and Power Diode Process and Simulation**

*Sunday, 18 December 2016 19:00 (1 hour)*

**Presenter:** SANDOW, Christian

**Session Classification:** Evening Talk



Contribution ID: 47

Type: **not specified**

## **Fraunhofer EMFT**

*Monday, 19 December 2016 20:00 (40 minutes)*

**Presenter:** KUTTER, Christoph

**Session Classification:** Evening Talk

Contribution ID: 48

Type: **not specified**

## New Devices

*Wednesday, 21 December 2016 09:00 (30 minutes)*

**Presenter:** TREIS, Johannes

**Session Classification:** Devices and Simulations